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# Author Correction: Interfacial stabilization for epitaxial CuCrO<sub>2</sub> delafossites

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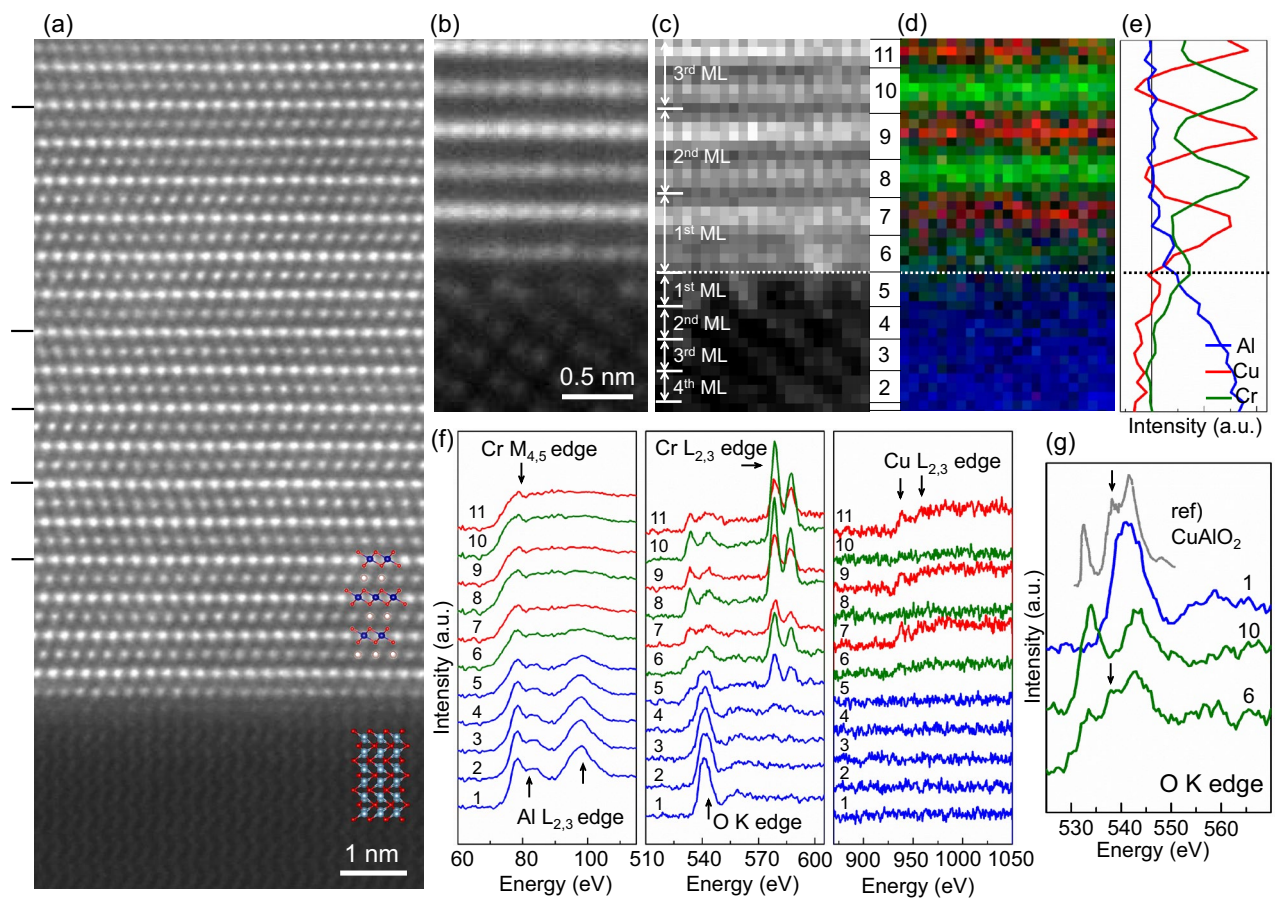
Correction to: *Scientific Reports* <https://doi.org/10.1038/s41598-020-68275-w>, published online 09 July 2020

The original version of this Article contained an error in Figure 3, panel (a), where the positioning of the atomic structure overlaid on the HAADF STEM image was incorrect.

The original Figure 3 and its accompanying legend appear below.

The original Article has been corrected.

Published online: 14 March 2023



**Figure 3.** (a, b) High-angle annular dark field (HAADF) scanning transmission electron microscopy (STEM) image of a  $\text{CuCrO}_2$  thin film grown on an  $\text{Al}_2\text{O}_3$  (0001) substrate seen along the (a)  $[\bar{1}100]$  and (b)  $[1000]$  zone axis. (c)–(f) Electron energy loss spectroscopy (EELS) spectrum imaging of the  $\text{CuCrO}_2/\text{Al}_2\text{O}_3$  interface seen along the  $[1000]$  zone axis. The monolayers (MLs) for  $\text{CuCrO}_2$  thin film and  $\text{Al}_2\text{O}_3$  substrate in the (0001) direction were defined as a set of Cu and  $\text{CrO}_2$  sublayers and a single  $\text{Al}_2\text{O}_3$  layer, respectively. (c) Simultaneously acquired HAADF-STEM image. (d) Color-coded composite elemental map with Al in blue, Cr in green, and Cu in red. (e) Integrated line profile of Al, Cr, and Cu signals in (d) across the interface. The dotted lines in (c)–(e) indicate the position of the  $\text{CuCrO}_2/\text{Al}_2\text{O}_3$  interface. (f) Layer-resolved integrated EELS spectra of Al- $L_{2,3}$ , Cr- $M_{4,5}$ , O- $K$ , Cr- $L_{2,3}$ , and Cu- $L_{2,3}$  edges. The position of the atomic layer corresponding to each EELS spectrum is indicated by the numerical index between (c) and (d). (g) EELS O- $K$  edge spectra of the  $\text{Al}_2\text{O}_3$  substrate,  $\text{CuCrO}_2$  thin film, and  $\text{Cr}_{1-x}\text{Al}_x\text{O}_2$  interface layer with an X-ray absorption spectroscopy (XAS) O- $K$  edge reference spectrum of  $\text{CuAlO}_2$ <sup>30</sup>. It is worth noting that no discernible vacancy-related features could be detected from the integrated line-profile spectra.



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